CLAIMS

What is claimed is:

4

1	1.	A circuit for setting a substrate voltage level comprising:				
2	,	a. means for maintaining a substrate at a first predetermined voltage level;				
3		b. means for maintaining the substrate at a second predetermined voltage level,				
4		wherein the second predetermined voltage level is higher than the first				
5		predetermined voltage level;				
6		c. means for maintaining the substrate at a third predetermined voltage level,				
		wherein the third predetermined voltage level is lower than the first				
2		predetermined voltage level.				
i U		Production				
u E	2.	The circuit according to claim 1 further comprising means for selecting between the				
7 189 4 4 4 7 2 4 4		rst predetermined level, the second predetermined level and the third predetermined level.				
ii F	kilot j					
	3.	The circuit according to claim of further comprising:				
	J.	a. means for maintaining the substrate at a fourth predetermined voltage level,				
fu Nj		wherein the fourth predetermined voltage level is higher than the second				
<u> </u>		predetermined voltage level; and				
		b. means for maintaining the substrate at a fifth predetermined voltage level,				
5		wherein the fifth predetermined voltage level is lower than the third				
6		predetermined voltage level.				
7		predetermined voltage level.				
		The circuit according to claim 3 further comprising means for selecting between the				
1	4.					
2		st predetermined level, the second predetermined level, the third predetermined level, the				
3	fourt	fourth predetermined level and the fifth predetermined level.				

1	5.	A circuit for setting a substrate voltage level comprising:
2	\	a. a plurality of resistive elements coupled to each other in a series to form a
3		chain of resistive elements, the chain having a first terminal and a second
4		terminal;
5		b. a reference voltage source coupled to the first terminal;
6		c. a substrate coupled to the second terminal; and
7		d. a plurality of switches wherein each switch is coupled to bypass at least one of
8		the resistive elements.
1	6.	The circuit according to claim 5 wherein the resistive elements each have non-linear
2	resist	ances.
IJ Ł	7.	The circuit according to claim 5 wherein the resistive elements comprise diodes.
	8.	The circuit according to claim 5 wherein the resistive elements comprise MOSFETs.
	9.	The circuit according to claim 5 wherein the switches comprise MOSFETs.
W T		
ī	10.	The circuit according to claim 5 further comprising a charge pump coupled to control
2	the s	ubstrate voltage level.
1	11.	A circuit for setting a substrate voltage level comprising:
2		a. a first n-channel MOSFET having a first gate, a first drain and a first source
3		wherein the first gate is coupled to the first drain and the first gate is coupled
4		to a voltage reference level;
		\

PATENT Atty. Docket No. MICRON-01023

5	'	\ b.	a second n-channel MOSFET having a second gate, a second drain and a		
6			second source wherein the second gate is coupled to the second drain and the		
7		- \	second gate is coupled to the first source;		
8		c.	a third n-channel MOSFET having a third gate, a third drain and a third source		
9			wherein the third gate is coupled to the third drain and the third gate is coupled		
10			to the second source;		
11		d.	a forth n-channel MOSFET having a forth gate, a forth drain and a forth source		
12			wherein the forth gate is coupled to be controlled by a first control voltage and		
13			the forth drain is coupled to the third drain and the forth source is coupled to		
14			the third source;		
15 📮		e.	a fifth n-channel MOSFET having a fifth gate, a fifth drain and a fifth source		
			wherein the fifth gate is coupled to the third gate and the fifth drain is coupled		
16 © 17 E			to the third source and the fifth source is coupled to a substrate; and		
18 📜		f.	a sixth n-channel MOSFET having a sixth gate, a sixth drain and a sixth source		
19. Ē			wherein the sixth drain is coupled to the fifth drain and the sixth source is		
20 🗒			coupled to the fifth source and the sixth gate is coupled to be controlled by a		
21 5			second control voltage.		
T.					
1 4	12.	The c	ircuit according to claim 11 further comprising a charge pump having a input		
2	terminal and an output terminal, wherein the input terminal is coupled to the first source and				
3	the ou	tput ter	rminal is coupled to the substrate.		
1	13.	The c	ircuit according to claim 11 further comprising:		
2		a.	a seventh n-channel MOSFET having a seventh gate, a seventh drain and a		
3			seventh source wherein the seventh gate is coupled to the fifth gate, the seventh		
4			drain is coupled to the fifth source and the seventh source is coupled to the		
5			substrate; and		

1

2

3

2

6

7

8

9

1

2

b.	an eighth n-channel MOSFET having an eighth gate, an eighth drain and an
	eighth source, wherein the eighth gate is coupled to be controlled by a third
	control voltage level, the eighth drain is coupled to the seventh drain and the
	eighth source is coupled to the seventh source.

- 14. The circuit according to claim 13 further comprising a charge pump having a input terminal and an output terminal, wherein the input terminal is coupled to the first source and the output terminal is coupled to the substrate.
 - 15. The circuit according to claim 13 further comprising:
 - a. a ninth n-channel MOSFET having a ninth gate, a ninth drain and a ninth source wherein the ninth gate is coupled to the seventh gate, the ninth drain is coupled to the seventh source and the ninth source is coupled to the substrate; and
 - b. a tenth n-channel MOSFET having a tenth gate, a tenth drain and a tenth source, wherein the tenth gate is coupled to be controlled by a forth control voltage level, the tenth drain is coupled to the ninth drain and the tenth source is coupled to the ninth source.
 - 16. The circuit according to claim 15 further comprising a charge pump having a input terminal and an output terminal, wherein the input terminal is coupled to the first source and the output terminal is coupled to the substrate.
- 1 17. A method of testing integrated circuit chips comprising the steps of:
 - a. setting a voltage level of a substrate to a first predetermined level; and

3		6.	setting the volta	age level of the substrate to a second predetermined	level
4			wherein the seco	ond predetermined level is higher than the first pred	letermined
5			level.	•	
1	18.	A me	ethod of testing int	tegrated circuit chips comprising the steps of:	
2	10.	a.		e level of a substrate to a first predetermined level;	and
3		b.	_	age level of the substrate to a second predetermined	
4				ond predetermined level is lower than the first prede	
5			level.		
, beer			•		
	Q_{G}				
H	nut				-
	k,				
\$:					
ing god god day to the					
Harry Harry					
					-
E to-The					